

Notice of References Cited		Application/Control No. 10/665,024	Applicant(s)/Patent Under Reexamination MCKEE ET AL.	
		Examiner <i>K. A.</i> Kamran Afshar, 571-272-7796	Art Unit 2681	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,424,251 B1	07-2002	Byrne, Matthew T.	340/7.58
	B	US-6,269,256 B1	07-2001	Nakamura, Taisuke	455/567
	C	US-5,924,046	07-1999	Martensson, Nils Erik Vilhelm	455/567
	D	US-2002/0010008 A1	01-2002	Bork et al.	455/567
	E	US-2003/0045265 A1	03-2003	Huang et al.	455/219
	F	US-5,404,391	04-1995	Wavroch et al.	455/567
	G	US-6,032,058	02-2000	Higuchi et al.	455/567
	H	US-2002/0137552 A1	09-2002	Cannon et al.	455/567
	I	US-2005/0018834 A1	01-2005	Furnas, William J.	379/376.02
	J	US-6,052,563	04-2000	Macko, William J.	340/7.54
	K	US-2004/0132426 A1	07-2004	Baiker, Stefan	455/403
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.